

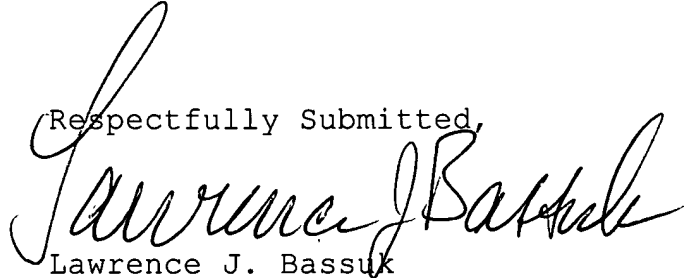
In the Claims:

1. (original) A wafer test system comprising:
a wafer having a plurality of die to be tested,
a tester having stimulus and response outputs,
and a connection formed between said plurality of die
and tester outputs.

Claims 2-11. (canceled)

Applicant respectfully requests examination of this application.

Respectfully Submitted,

A handwritten signature in cursive script, reading "Lawrence J. Bassuk". The signature is written in black ink and is positioned above the printed name and title.

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